

## AMENDMENTS

Please replace the claims, including all prior versions, with the listing of claims below.

### LISTING OF CLAIMS:

1. (Currently Amended) A magnetic recording medium comprising a substrate, an underlayer possessing an fcc lattice structure, and a magnetic layer with an hcp (101-2) plane being parallel to the surface of the substrate, wherein an easy magnetization axis in the magnetic layer is tilted away from the (101-2) plane.
2. (Original) The magnetic recording medium of claim 1, wherein the (101-2) plane is a Co(101-2) plane.
3. (Original) The magnetic recording medium of claim 1, wherein the easy magnetization axis is tilted about 45° away from the (101-2) plane.
4. (Original) The magnetic recording medium of claim 2, wherein the easy magnetization axis is tilted about 45° away from the surface of the substrate.
5. (Canceled)
6. (Currently Amended) The magnetic recording medium of claim [[5]] 1, wherein a mismatch between the lattice unit of the underlayer material and that of the hcp lattice of the magnetic material of the magnetic layer is less than 10%.
7. (Currently Amended) The magnetic recording medium of claim [[5]] 1, wherein the underlayer is directly in contact with the magnetic layer.

8. (Currently Amended) The magnetic recording medium of claim [[5]] 1, wherein the magnetic material is Co or a Co-containing alloy.

9. (Canceled)

10. (Currently Amended) The magnetic recording medium of claim [[9]] 1, wherein the underlayer material is selected from the group consisting of Ni, Al, Rh, Pd, Ag, Ir, Pt, Au, Pb, Th, Ce and Yb.

11. (Currently Amended) A method of manufacturing a magnetic recording medium comprising obtaining a substrate, depositing an underlayer possessing an fcc lattice structure, and depositing a magnetic layer on the substrate, the magnetic layer comprising a magnetic material with an hcp (101-2) plane being parallel to a surface of the substrate, wherein an easy magnetization axis in the magnetic layer is tilted away from the (101-2) plane.

12. (Original) The method of claim 11, wherein the (101-2) plane is a Co(101-2) plane.

13. (Original) The method of claim 11, wherein the easy magnetization axis is tilted about 45° away from the (101-2) plane.

14. (Original) The method of claim 12, wherein the easy magnetization axis is tilted about 45° away from the surface of the substrate.

15. (Canceled)

16. (Currently Amended) The method of claim [[15]] 11, wherein a mismatch between the lattice unit of the underlayer material and that of the hcp lattice of the magnetic material of the magnetic layer is less than 10%.

17. (Currently Amended) The method of claim [[15]] 11, wherein the underlayer is directly in contact with the magnetic layer.

18. (Currently Amended) The method of claim [[15]] 11, wherein the magnetic material is Co or a Co-containing alloy.

19. (Canceled)

20. (Currently Amended) The method of claim [[19]] 11, wherein the underlayer material is selected from the group consisting of Ni, Al, Rh, Pd, Ag, Ir, Pt, Au, Pb, Th, Ce and Yb.

21. (Canceled)